

100V Dual N-Channel MOSFETs

General Description

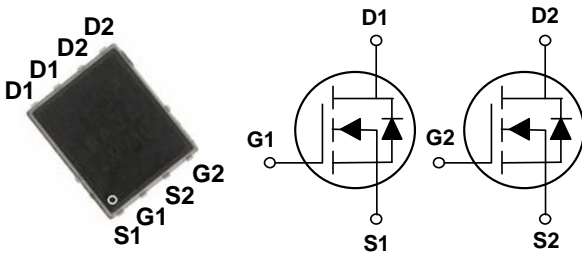
These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BV_{DSS}	$R_{DS(ON)}$	I_D
100 V	19 m Ω	40 A

Features

- $R_{DS(ON)} \leq 19m\Omega @ V_{GS}=10V$
- Improved dv/dt Capability
- Fast Switching
- Green Device Available

PPAK5X6 Dual Pin Configuration



Applications

- Synchronous Rectification
- DC/DC Converter
- Power Management Switches

Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Drain Current - Continuous ($T_C=25^\circ\text{C}$)	40	A
	Drain Current - Continuous ($T_C=100^\circ\text{C}$)	24	
I_{DM}	Drain Current - Pulsed (NOTE 1)	160	A
EAS	Single Pulse Avalanche Energy (NOTE 2)	64	mJ
P_D	Power Dissipation ($T_C=25^\circ\text{C}$)	72	W
	Power Dissipation ($T_C=70^\circ\text{C}$)	46	
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
Marking Code		NM020B	

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{\theta JA}$	Thermal Resistance Junction to Ambient (NOTE 3)	62	$^\circ\text{C/W}$
$R_{\theta JC}$	Thermal Resistance Junction to Case	1.74	$^\circ\text{C/W}$

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Electrical Characteristics (T_J=25°C, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250uA	100	---	---	V
I _{DSS}	Drain-Source Leakage Current	V _{DS} =100V, V _{GS} =0V, T _J =25°C	---	---	1	uA
		V _{DS} =100V, V _{GS} =0V, T _J =100°C	---	---	100	
I _{GSS}	Gate-Source Leakage Current	V _{GS} =±20V, V _{DS} =0V	---	---	±100	nA

On Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
R _{DS(ON)}	Static Drain-Source On-Resistance (NOTE 4)	V _{GS} =10V, I _D =20A	---	16	19	mΩ
		V _{GS} =4.5V, I _D =10A	---	---	24	
V _{GS(th)}	Gate Threshold Voltage	V _{GS} =V _{DS} , I _D =250uA	1.0	---	2.5	V
g _{fs}	Forward Transconductance	V _{DS} =10V, I _D =2A	---	35	---	S

Dynamic and switching Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
Q _g	Total Gate Charge	V _{DS} =50V, V _{GS} =10V, I _D =8A	---	19.8	---	nC
Q _{gs}	Gate-Source Charge		---	2.4	---	
Q _{gd}	Gate-Drain Charge		---	5.3	---	
T _{d(on)}	Turn-On Delay Time	V _{DD} =50V, V _{GS} =10V, R _G =2.2Ω, I _D =10A	---	17.8	---	nS
T _r	Rise Time		---	3.9	---	
T _{d(off)}	Turn-Off Delay Time		---	33.5	---	
T _f	Fall Time		---	3.2	---	
C _{iss}	Input Capacitance	V _{DS} =50V, V _{GS} =0V, F=1MHz	---	1190	---	pF
C _{oss}	Output Capacitance		---	194.6	---	
C _{rss}	Reverse Transfer Capacitance		---	4.1	---	
R _g	Gate Resistance	V _{DS} =V _{GS} =0V, F=1MHz	---	2	---	Ω

Drain-Source Diode Characteristics and Ratings

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I _S	Continuous Source Current	V _G =V _D =0V, Force Current	---	---	40	A
I _{SM}	Pulsed Source Current		---	---	80	A
V _{SD}	Diode Forward Voltage (NOTE 4)	V _{GS} =0V, I _S =1A	---	---	1.2	V

NOTES :

1. Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C
2. V_{DD}=25V, V_{GS}=10V, L=0.5mH, I_{AS}=16A.
3. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
4. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.

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Characteristics Curves

Fig.1 Typ. Output Characteristics

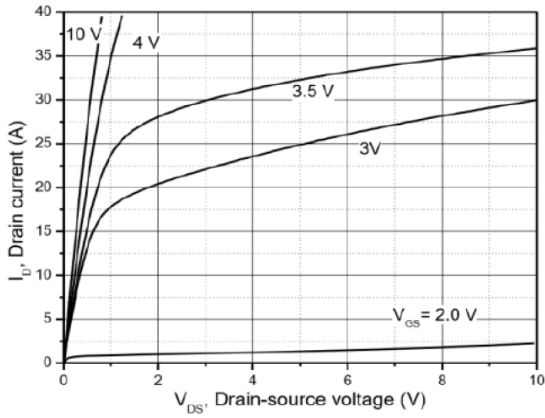


Fig.2 Typ. Transfer Characteristics

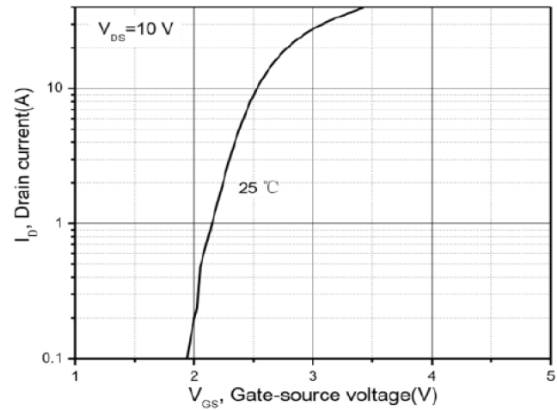


Fig.3 Typ. Capacitance

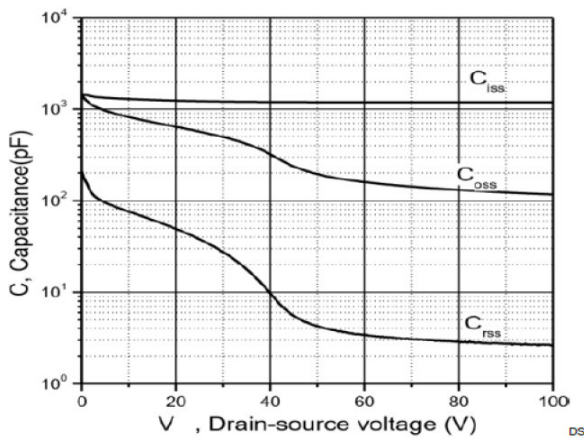


Fig.4 Typ. Gate Charge

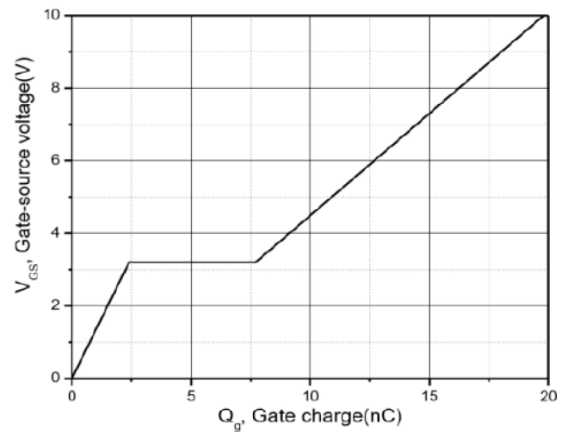


Fig.5 Drain-Source Breakdown Voltage

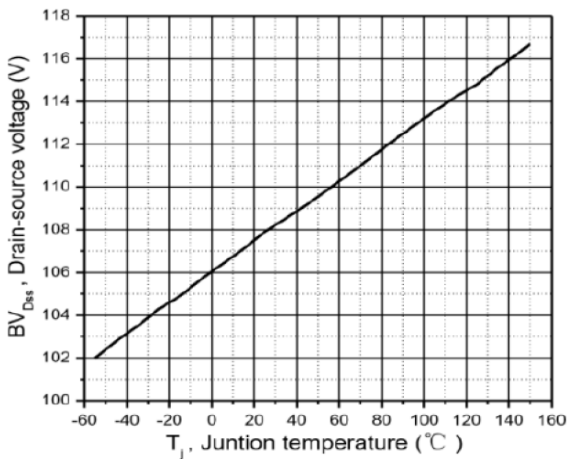
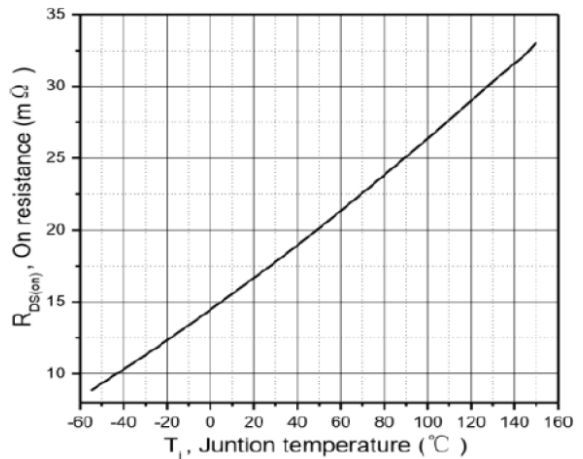


Fig.6 Drain-Source On-State Resistance



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Characteristics Curves

Fig.7 Forward Characteristic of Body Diode

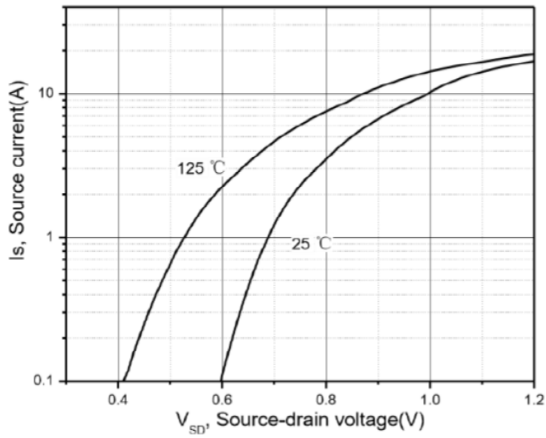


Fig.8 Drain-Source On-State Resistance

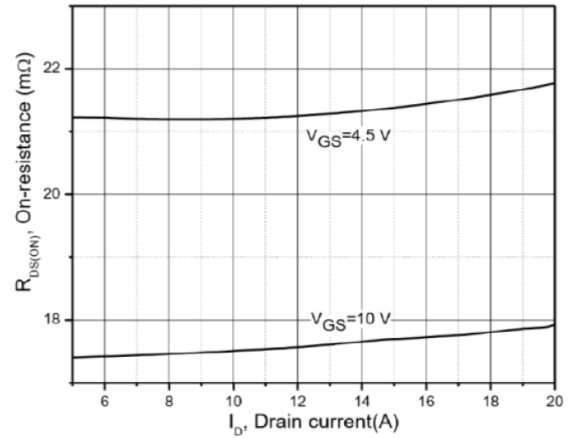
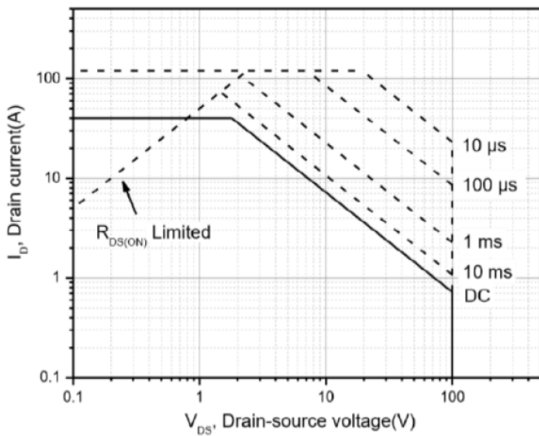
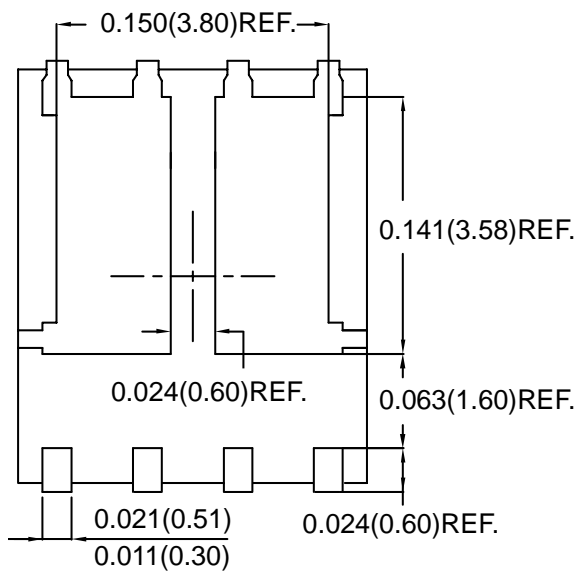
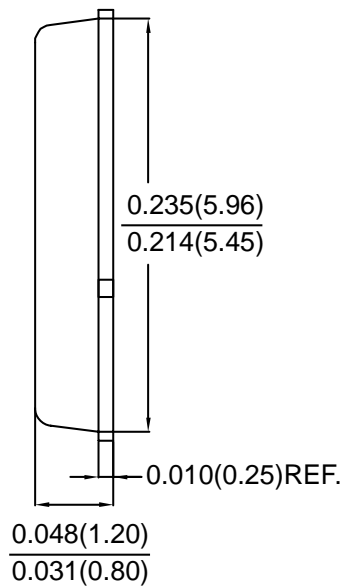
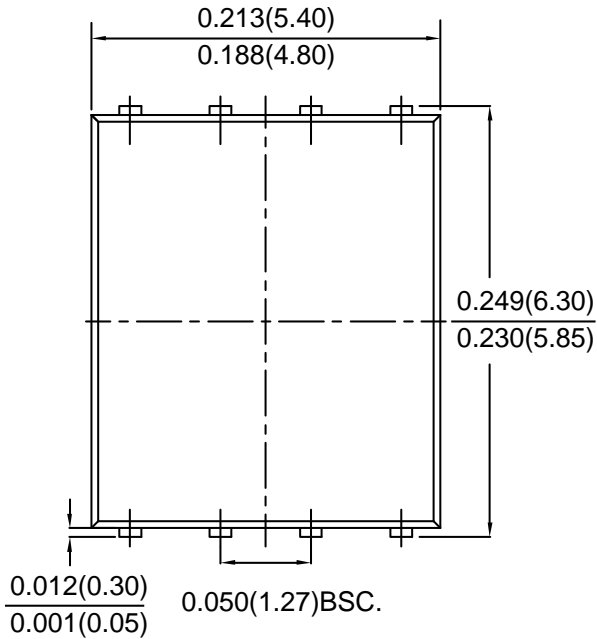


Fig.9 Safe Operating Area



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Package Outline Dimensions



PPAK5X6 Dual

Dimensions in inches and (millimeters)

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